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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/517,456	FALCK ET AL.	
Examiner	Art Unit	
SIMON D. NGUYEN	2618	

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Class	Subclass	Date	Examiner
370 ·	311- 313,,319, 326,	2/5/2007	SDN
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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